Flow Dynamics of Spheromaks in SSX

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Introduction

-The Swarthmore Spheromak Experiment (SSX) is designed to study both basic plasma physics (reconnection) and fusion-related science (spheromaks and FRCs). Plasma flow is a central theme in both cases. Reconnection generates Alfvenic plasma outflow and our formation scheme can generate strong flows in spheromaks and FRCs.

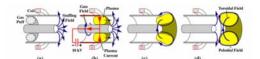


Figure 1. Schematic of spheromak formation in SSX. Spheromaks are ejected at 100 km/s.

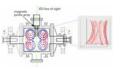


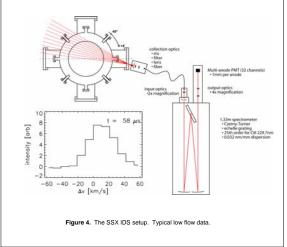
Figure 2. Spheromak merging in SSX. Measured 3D reconnection structure (right).



Figure 3. Plasma discharge in SSX (H plasma). Soft x-ray array is depicted (top).

Ion Doppler Spectroscopy (IDS)

-Our primary diagnostic to measure line averaged flow is IDS. The SSX IDS instrument measures with 1 µs time resolution the width and Doppler shift of CIII impurity (H plasma) 229.7 nm line to determine Ti and line- averaged flow velocity.



Mach Probe Studies



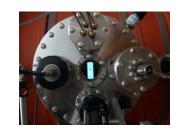


Figure 5. Mach probe schematic. Larger Mach II (top), smaller Mach I in He GDC plasma (bottom)

Vacuum Ultraviolet and Soft X-ray

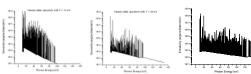


Figure 6. Calculated spectra with T = 12, 28, and 44 eV. 0.1% C, N, and O impurities. Calculations performed with PrismSpect.

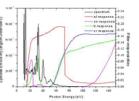


Figure 7. SXR filter response functions for photodiodes filtered by thin films of AI, Ti, Sn, and Zr



Figure 8. 0.2 m VUV monochrometer

on SSX

Figure 9. SXR filtered diode array

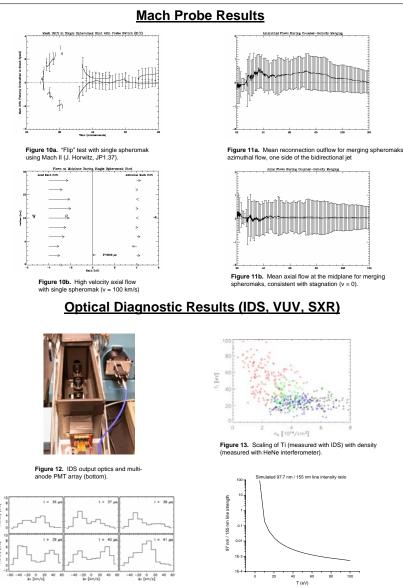


Figure 14. Bidirectional reconnection jets during counter-helicity merging (C. Cothran).

Acknowledgements

Figure 15. Te from CIII (97.7 nm) to CIV (155

nm) ratio (V. Chaplin, JP1.38)

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